

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 6,937,049 B2  
DATED : August 30, 2005  
INVENTOR(S) : Sylvie Wuidart and Claude Zahra

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Column 3.

Line 45, should read:

-- interval  $\Delta t$  from step 20, an answer request (block 23, SEND --.

Column 6.

Line 32, should read:

-- said second control signal --.

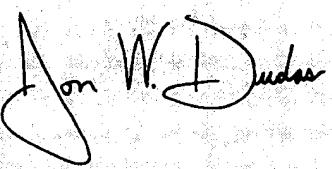
Lines 43-48, should read:

-- 11. A system for testing a set of identical integrated circuit chips in parallel,  
comprising:

a plural of physical contact pairs intended to contact pads of the respective chips;  
and for  
transmitting, from a tester a first test control signal to --.

Signed and Sealed this

Eighth Day of November, 2005



JON W. DUDAS  
Director of the United States Patent and Trademark Office